NOIDA INSTITUTE OF ENGINEERING AND TECHNOLOGY, GREATER NOIDA

(An Autonomous Institute)



Affiliated to

DR. A.P.J. ABDUL KALAM TECHNICAL UNIVERSITY, LUCKNOW



Evaluation Scheme & Syllabus

For

M. Tech in VLSI Design - First Year

(Effective from the Session: 2020-21)

NOIDA INSTITUTE OF ENGINEERING & TECHNOLOGY, GREATER NOIDA (An Autonomous Institute)

M. TECH (VLSI DESIGN)

Evaluation Scheme SEMESTER I

Sl.	Subject	Subject	Po	eriod	ls	E	Evaluat	ion Scheme	S	Er Semo		Total	Credit
No.	Codes		L	T	P	CT	TA	TOTAL	PS	TE	PE		
		CMOS Digital VLSI											
1	AMTVL0101	Design	3	0	0	20	10	30		70		100	3
		Advanced Digital											
		Design using											
2	AMTVL0102	Verilog	3	0	0	20	10	30		70		100	3
		Research Process											
3	AMTCC0101	and Methodology	3	0	0	20	10	30		70		100	3
5		Elective -I*	3	0	0	20	10	30		70		100	3
6		Elective -II*	3	0	0	20	10	30		70		100	3
		CMOS Digital VLSI											
7	AMTVL0151	Design Lab	0	0	4				20		30	50	2
		Advanced Digital											
		Design Lab using											
8	AMTVL0152	Verilog	0	0	4				20		30	50	2
		TOTAL										600	19

(*) Refer the Electives list

Elective I*:

- 1. AMTVL0111 Microelectronics
- 2. AMTVL0112 MOS Device Modeling
- 3. AMTVL0113 Analog IC Design

Elective II*:

- 1. AMTVL0114 Microchip Fabrication Technology
- 2. AMTVL0115 Clean Room Technology and Maintenance
- 3. AMTVL0116 ULSI Technology

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M. TECH (VLSI DESIGN)

Evaluation Scheme SEMESTER II

Sl.	Subject	Subject]	Perio	ods]	Evalua	tion Scheme	s		nd ester	Total	Credit
No	Codes	•	L	T	P	CT	TA	TOTAL	PS	TE	PE		
1	AMTVL0201	Digital Design Using FPGA and CPLD	3	0	0	20	10	30		70		100	3
2	AMTVL0202	Low Power VLSI Design	3	0	0	20	10	30		70		100	3
3		Elective –III*	3	0	0	20	10	30		70		100	3
4		Elective- IV*	3	0	0	20	10	30		70		100	3
5		Elective- V*	3	0	0	20	10	30		70		100	3
6	AMTVL0251	Digital Design Using FPGA and CPLD Lab	0	0	4				20		30	50	2
7	AMTVL0252	Low Power VLSI Design Lab	0	0	4				20		30	50	2
8	AMTVL0253	Seminar-I	0	0	2				50			50	1
		TOTAL										650	20

(*) Refer the Electives list

Elective III*:

- 1. AMTVL0211 VLSI Testing and Testability
- 2. AMTVL0212 VLSI DSP Architectures
- 3. AMTVL0213 Full Custom Design

Elective IV*:

- 1. AMTVL0214 MEMS Sensor Design
- 2. AMTVL0215 Nanoscale Devices: Modeling & Simulation
- 3. AMTVL0216 Physical Design & Automation

Elective V*:

- 1. AMTVL0217 Embedded Microcontrollers
- 2. AMTVL0218 Real Time Operating System
- 3. AMTVL0219 SOC Design using ARM

M. TECH FIRST YEAR					
Course Code	AMTVL0101	LTP	Credit		
Course Title	CMOS Digital VLSI Design	3 0 0	03		
Course Object	tive:		1		
1	To explain basics of MOS switch, MOS fabrication and				
	their characteristics.				
2	To explain basic concept of CMOS inverter operation, its				
	characteristics and switching power dissipation.				
3	To design static CMOS combinational and sequential				
4	logic at the transistor level, including mask layout.				
5	To explain the concept of dynamic logic circuits.				
3	To design functional units including ROMs, SRAMs, and DRAM.				
Pre-requisites	: Basics of CMOS.				
11c-requisites					
UNIT-I	Course Contents / Syllabus MOS TRANSISTOR BASIC	101	201186		
			nours		
	Basic, MOS switch, VLSI Design flow & Y-Chart, Basic		_		
_	equation and second order effect, Fabrication Process Flow: Basic Steps, The CMOS n-Well Process, Layout Design Rules, MOS inverters: DC transfer characteristics, latchup, MOSFET				
capacitances.	Design Rules, WOS inverters. De transfer enaracteristics	, iatenup,	MOSILI		
UNIT-II	CMOS INVERTER		9hours		
Switching characteristic delay constraints,	n of CMOS inverter, Supply voltage scaling, power and terristic: Delay time definition, calculation of delay times, Switching Power dissipation of CMOS inverter.		esign with		
UNIT-III	COMBINATIONAL & SEQUENTIAL MOS LOGIC CIRCUITS		8hours		
circuits design – OIA gates, CMOS Sequential MOS	Combinational MOS Logic Circuits: MOS logic circuits with NMOS loads, Complex Logic circuits design – Realizing Boolean expressions using NMOS gates and CMOS gates, AOI and OIA gates, CMOS full adder, CMOS transmission gates, Designing with Transmission gates, Sequential MOS Logic Circuits: Behavior of bi-stable elements, D latch, SR Latch, Clocked latch and flip flop circuits, CMOS, and edge triggered flip-flop.				
UNIT-IV	DYNAMIC LOGIC CIRCUITS		9hours		
Logic Circuits: I	Logic Circuits: Basic principle of pass transistor circuits, Voltage Bootstrapping, Synchronous dynamic circuit techniques, Dynamic CMOS transmission gate logic, High performance Dynamic				
UNIT-V	SEMICONDUCTOR MEMORIES		8 hours		
	Memories: Types, RAM array organization, DRAM – Types,	Operation			
currents in DRAM cell and refresh operation, SRAM operation Leakage currents in SRAM cells, Flash Memory- NOR flash and NAND flash					
-	me:After successful completion of this course students will be	be able to			
CO 1	To identifythe fabrication process of CMOS transistor.				

CO 2	To identify basic concept of CMOS inverter operation, its	
	characteristics and switching power dissipation.	
CO 3	Design combinational & Sequential MOS logic circuits	
	like latches and flip flops.	
CO 4	Explain and design synchronous dynamic pass transistor	
	circuits	
CO 5	Analyse SRAM cell and memory arrays.	

Text Books

- 1. Sung-Mo Kang & Yusuf Leblebici, CMOS Digital Integrated Circuits Analysis & Design, , MGH, Third Ed., 2003
- 2. Jan M Rabaey, Digital Integrated Circuits A Design Perspective, Prentice Hall, Second Edition, 2005
- 3. David A. Hodges, Horace G. Jackson, and Resve A. Saleh, Analysis and Design of Digital Integrated Circuits, Third Edition, McGraw-Hill, 2004

- 1. R. J. Baker, H. W. Li, and D. E. Boyce, CMOS circuit design, layout, and simulation, Wiley-IEEE Press, 2007
- 2. Christopher Saint and Judy Saint, IC layout basics: A practical guide, McGraw-Hill Professional, 2001

M. TECH FIRST YEAR						
Course Code	AMTVL0102	LTP	Credit			
Course Title	Advanced Digital Design using Verilog	3 0 0	03			
Course Object	ive:	1	1			
1	1 Study and explain the basic concepts Verilog HDL.					
2	Implement digital circuits using distinct design sty	yles.				
3	Design and synthesis digital circuits using HDLs.					
4	Study the concepts of data path design and switch modeling.	level				
5	Explain about pipelining and processor design.					
Pre-requisites:	Digital System Design					
	Course Contents / Syllabus					
UNIT-I	INTRODUCTION TO HARDWARE DESC LANGUAGE (HDL)	RIPTION	8 hours			
Introduction to hardware description language (HDL), Verilog language and data types Digital System Design Process, Hardware modeling, Introduction to hardware description language (HDL), Verilog language features, elements of Verilog, Top-Down, Bottom-up Design, Verilog operators, Data types in Verilog; net type, reg type, wire type, Verilog Models of propagation delay						
and net delay path	delays and simulation, inertial delay effects and pu	ılse rejectio	n			
UNIT-II	JNIT-II DISTINCT DESIGN STYLES 8 hours					
flow level, proce	on styles, behavioral and structural design style, Vedural assignment, blocking / non-blocking assign assign writing Verilog test benches.					
UNIT-III	SYNTHESIS OF COMBINATIONAL & SEQUENTIAL LOGIC		8 hours			
sequential logic,	HDL-based synthesis - technology-independent design, styles for synthesis of combinational and sequential logic, synthesis of finite state machines, synthesis of gated clocks, design partitions and hierarchical structures.					
UNIT-IV	NIT-IV DATA PATH AND CONTROLLER DESIGN					
	tate machines, Data-path and Controller Design, S ig register banks, Switch level modeling.	ynthesizabl	le Verilog, Modeling			
UNIT-V						
Basic pipelining concepts, Pipeline modeling, Pipeline implementation of a processor, Verilog modeling of the processor.						
Course Outcome: After successful completion of this course students will be able						
to						
CO 1	Outline the basic concepts Verilog HDL.					
CO 2	CO 2 Design of digital circuits using distinct design styles.					
CO 3	Model HDL based Synthesis of digital circuits.					
CO 4 Analyze the concepts of data path design and switch level						

	modeling.	
CO 5	Implement pipelining and processor design using Verilog modeling.	

- 1. Navabi, Z., 1999. Verilog digital system design. McGraw-Hill.
- 2. Palnitkar, S., 2003. Verilog HDL: a guide to digital design and synthesis (Vol. 1). Prentice Hall Professional.
- 3. Arnold, M.G., 1998. Verilog digital computer design: Algorithms into hardware. Prentice-Hall, Inc.

- 1. Lin, M.B., 2008. Digital system designs and practices: using Verilog HDL and FPGAs. Wiley Publishing.
- 2. Unsalan, C. and Tar, B., 2017. Digital system design with FPGA: implementation using Verilog and VHDL. McGraw-H

Link:	
Unit 1	https://www.youtube.com/watch?v=wiNDn19GpRU&list=PLUtfVcb-iqn-EkuBs3arreilxa2UKIChl&index=3
Unit 2	https://www.youtube.com/watch?v=xWimKdisUXE&list=PLUtfVcb-iqn-EkuBs3arreilxa2UKIChl&index=12
Unit 3	https://www.youtube.com/watch?v=lpS3S2gVoB4&list=PLUtfVcb-iqn-EkuBs3arreilxa2UKIChl&index=23
Unit 4	https://www.youtube.com/watch?v=cIDoJtYdDVA&t=66s
Unit 5	https://www.youtube.com/watch?v=w1u338oIeTQ

Course C	ode AMTCC0101	LTP	Credit		
Course Ti	itle Research Process & Methodology	3 0 0	03		
Course Objective:					
1	To explain the concept / fundamentals of research and their types				
2	To study the methods of research design and steps of research process				
3	To explain the methods of data collection and procedure of sampling techniques				
4	To analyze the data, apply the statistical techniques and understand the concept of hypothesis testing				
5	To study the types of research report and technical writing.				

Course Contents / Syllabus

INTRODUCTION TO RESEARCH **UNIT-I**

Definition, objective and motivation of research, types and approaches of research, Descriptive vs. Analytical, Applied vs. Fundamental, Quantitative vs. Qualitative, Conceptual vs. Empirical, Research methods versus Methodology, significance of research, criteria of good research.

RESEARCH FORMULATION AND DESIGN UNIT-II

8 hours

8 hours

Research process and steps involved, Definition and necessity of research problem. Importance and objective of Literature review, Locating relevant literature, Reliability of a source, Writing a survey and identifying the research problem, Literature Survey, Research Design, Methods of research design.

DATA COLLECTION UNIT-III

8 hours

Classification of Data, accepts of method validation, Methods of Data Collection, Collection of primary and secondary data, sampling, need of sampling, sampling theory and Techniques, steps in sampling design, different types of sample designs, ethical considerations in research.

UNIT-IV DATA ANALYSIS

8 hours

Processing Operations, Data analysis, Types of analysis, Statistical techniques and choosing an appropriate statistical technique, Hypothesis Testing, Data processing software (e.g. SPSS etc.), statistical inference, Chi-Square Test, Analysis of variance(ANOVA) and covariance, Data Visualization – Monitoring Research Experiments ,hands-on with LaTeX.

TECHNICAL WRITING AND REPORTING OF RESEARCH **UNIT-V** 8 hours

Types of research report: Dissertation and Thesis, research paper, review article, short communication, conference presentation etc., Referencing and referencing styles, Research Journals, Indexing, citation ofJournals and Impact factor. **Types** of Indexing-SCI/SCIE/ESCI/SCOPUS/DBLP/Google Scholar/UGC-CARE etc. Significance of conferences and their ranking, plagiarism, IPR- intellectual property rights and patent law, commercialization, copy right, royalty, trade related aspects of intellectual property rights (TRIPS); scholarly publishing- IMRAD concept and design of research paper, reproducibility and accountability.

Course outcome: Upon completion of the course, the student will be able to

CO 1	Explain concept / fundamentals for different types of research	
CO 2	Apply relevant research Design technique	
CO 3	Use appropriate Data Collection technique	
CO 4	Evaluate statistical analysis which includes various parametric test and non-parametric test and ANOVA technique	
CO 5	Prepare research report and Publish ethically.	_

- **1.** C. R. Kothari, Gaurav Garg, Research Methodology Methods and Techniques, New Age International publishers, Third Edition.
- **2.** Ranjit Kumar, Research Methodology: A Step-by-Step Guide for Beginners, 2nd Edition, SAGE 2005.
- 3. Deepak Chawla, NeenaSondhi, Research Methodology, Vikas Publication

Reference Books

- 1. Donald Cooper & Pamela Schindler, Business Research Methods, TMGH, 9th edition
- **2.** Creswell, John W., Research design: Qualitative, quantitative, and mixed methods approaches sage publications, 2013

NPTEL/ You tube/ Faculty Video Link:

M. TECH FIRST YEAR					
Course C	ode	AMTVL0151	LTP	Credit	
Course T	itle	CMOS Digital VLSI Design Lab	0 0 4	02	
		List of Experiment		•	
Sr. No.	Nan	Name of Experiment			
1	Study	y of Microwind software and its features.			
2	Desig	gn, simulate and verify the stick diagram of CMOS Inverter usi	ng Microw	ind.	
3		gn, simulate and verify the result of universal gates using Micro NAND (b) NOR	owind		
4		gn, simulate and verify theresult of following gates using Micro KOR (b) XNOR	owind		
5	Design, simulate and verify the operation of logic function using Microwind $Y = ((B+CD)(E+F))$ '				
6		gn, simulate and verify the operation of CMOS half adder using			
7	Design, simulate and verify the operation of CMOS full adder using two half adders in Microwind.				
8	Design, simulate and verify the operation of 4:1 Multiplexer in Microwind.				
9	Design, simulate and verify the operation of logic function using Dynamic and Domino				
	logic in Microwind: $Y = ((B + CD)(E + F))$				
10	Desig	gn, simulate and verify pseudo NMOS Inverter.			
		outcome: After completion of this course students will be a	ble to		
CO 1	_	yze the features of Microwind software.			
CO 2		gn, simulate and verify the result of universal gates, XOR, XN			
CO 3		gn, simulate and verify the operation of logic function using Mi			
CO 4		gn, simulate and verify the operation of CMOS half/full adder u		owind.	
	CO 5 Design, simulate and verify the operation of Multiplexer in Microwind.				
Link:					
•	https://www.youtube.com/watch?v=F-8_caipPsY				
https://www.youtube.com/watch?v=S1VOEqApQvA					
https://www.youtube.com/watch?v=EHUJda2ttU8					
https://wwv	v.youtu	ube.com/watch?v=yHJmFuexWbM			
https://wwv	v.youtu	ube.com/watch?v=7K_0I6CjBOY			

M. TECH FIRST YEAR				
Course Code	AMTVL0152	LTP	Credit	
Course Title	Advanced Digital Design Lab using Verilog	0 0 4	02	

Modeling and Functional Simulation of the following digital circuits (with Xilinx/ModelSim tools) using Verilog Hardware Description Language.

	, , , , , , , , , , , , , , , , , , , ,
Sr. No.	Name of Experiment
1	Design and simulate the Verilog HDL code to describe the functions of a Full
	Adder and Subtractor using three modeling styles.
2	Design and simulate the Verilog HDL code for the following
	combinational circuits:
	a) 4x1 Multiplexer using gate level modeling
	b) 8x1 Multiplexer using dataflow level modeling
	c) 4-Bit Binary to Gray Code Converter using structural
	modeling
3	Design and simulate the Verilog HDL code for the following combinational
	circuit:
	a) 3 to 8 Decoder
4	b) 8 to 3 Encoder
4	Design and simulate the Verilog HDL code for the following
	combinational circuits using structural modeling.
	a) 16x1 Multiplexer using 4x1 Mux b) 4. Bit Comparator using 1 Bit Comparator
5	b) 4- Bit Comparator using 1 Bit Comparator Design and simulate the Verilog HDL code for the basic arithmetic and
3	bitwise logical operations of ALU.
6	Design and simulate the Verilog HDL code for the flip-flops:
	a) SR FF
	b) JK FF
	c) DFF
	d) TFF
7	Design and simulate the Verilog HDL code for the following counters:
	a) 4- Bit Up-Down Counter
	b) BCD counter (Synchronous reset and asynchronous reset)
8	Design and simulate the Verilog HDL code for the following 4- Bit Shift
	register:
	a) SISO
	b) SIPO
	c) PIPO
	d) PISO
9	Design and simulate the Verilog HDL code for 4- Bit universal shift register.
10	Design and simulate the Verilog HDL code to detect the sequence 1010101.
	Outcome: After completion of this course students are able
CO 1	Translate the digital design into the Verilog HDL.
CO 2	Design the combinational circuits in Verilog HDL.
CO 3	Design the sequential circuits in Verilog HDL.

CO 4	Implement different digital circuits with component testing.
Link:	
Unit 1	https://www.youtube.com/watch?v=wiNDn19GpRU&list=PLUtfVcb-iqn-EkuBs3arreilxa2UKIChl&index=3
Unit 2	https://www.youtube.com/watch?v=xWimKdisUXE&list=PLUtfVcb-iqn-EkuBs3arreilxa2UKIChl&index=12
Unit 3	https://www.youtube.com/watch?v=lpS3S2gVoB4&list=PLUtfVcb-iqn-EkuBs3arreilxa2UKIChl&index=23
Unit 4	https://www.youtube.com/watch?v=cIDoJtYdDVA&t=66s
Unit 5	https://www.youtube.com/watch?v=w1u338oIeTQ

		M. TECH FIRST YEAR		
Course C	Code	AMTVL0111	LTP	Credit
Course T	itle	Microelectronics	3 0 0	03
Course C	Object	tive:	I	I
1	To pr	rovide the knowledge of different fabrication proc y, oxidation and their applications.	esses like	
2	To pro	ovide the knowledge of diffusion, ion implantation and of lithography and etching.		
3	To pro	ovide the knowledge of Discrete devices and its fabricat	ion.	
4	To pro	ovide the knowledge of Different digital logic circuits as s.	nd analog	
5	To pro	ovide the basic knowledge of BiCMOS ICs and their pa	ckaging.	
Pre-requ	isites	Basics of digital electronics, CMOS designing.		
		Course Contents / Syllabus		
UNIT-I		FABRICATION PROCESS	8 h	ours
		axy, Vapour phase epitaxy, Liquid phase epitaxy a n on insulators.	nd Molec	ular-Beam
Oxidati	on & F	Polysilicon Film Deposition: Thermal oxidation, Dielectallization & it's Application, Masking.	etric and I	Polysilicon
UNIT-II	,	DIFFUSION & ION IMPLANTATION		8 hours
dopants LITHO	s. GRAP	n, Distribution and range of implanted ions, Annealin HY & ETCHING: Optical lithography, X-ray lithography, lithography, Wet chemical etching and Dry chemical etching and	ohy, Ion li	
UNIT-II		DISCRETE DEVICE FABRICATION		8 hours
		f p-n junction, Bipolar junction transistor, JFET, well, N-well & Twin top Process)	MOSFE	Γ, CMOS
UNIT-IV	7	DESIGNING OF ANALOG AND DIGITAL CIRCUITS		8 hours
CMOS	Logic	For analog and digital ICs, functional elements available Circuits— Inverter, Two Input NOR Gate, Two Input Nos—single stage CE Amplifier and Emitter Follower.		
UNIT-V		BICMOS ICs		8 hours
Design	rs, cap	and Scaling, BICMOS ICs: Choice of transistor types pacitors, Packaging: Chip characteristics, package fu		nsistors,
Course C	Outco	me: After successful completion of this course stud	ents will l	e able to
CO 1		Identify different fabrication processes		
CO 2		Implement diffusion, ion implantation and different		

	types of lithography and etching.
CO 3	Explain Discrete devices and their fabrication.
CO 4	Design different digital logic circuits and analogcircuits
CO 5	Categorize BiCMOS ICs and their packaging.

- 1. Peter Van Zant, Microchip fabrication, McGraw Hill, 1997.
- 2. S.M. Sze, VLSI technology, McGraw-Hill Book company, NY, 1988.

- 1. S.K. Gandhi, 'VLSI Fabrication Principles'.
- 2. S.M. Sze, 'Semiconductor Devices Physics and Technology'.
- 3. Puckness Douglas A, Eshraghiaw Kamran "Basic VLSI Design" Prentice Hall (India)
- 4. K.R. Botkar, 'Integrated Circuits'

<u> </u>		M. TECH FIRST YEAR AMTVL0112	0 . 1	· <u>·</u>
Course C				<u>it</u>
Course Ti		MOS Device Modeling 3 0 0	03	
Course O				
		dy and analysis of MOS structure, its operations and , M	IOS as a	
	apacit			
		y and analysis of MOSFET Device Characteristics.	4 1	
-		ly and analysis of Mobility models, MOS Performance paramuency limitations.	neters and	
		ly and analysis of SOI MOSFET.		
		ly and analysis of SPICE Models for Semiconductor Devices.		
- -		Basic Electronics Engineering		
11c-1cqui	131103			
TINITE I	7	Course Contents / Syllabus MOS PHYSICS	0 1	
UNIT-I			8 hou	
		erfaces, Ideal MOS structure, MOS device in thermal equilibriu		
		ferences, charges in oxide, interface states, band diagram of a strostatics of a MOS (charge based calculations), calculating va		
C		nold voltage, MOS as a capacitor (2 terminal device), Three to		_
on threshold			Cilililai ivi	OS, effect
UNIT-II		MOSFET DEVICE CHARACTERISTICS		8 hours
	aracter	sistors: MOSFET- basic operation and fabrication; threshold istics of MOSFET, short channel and Narrow width effects		
Small signa	l mod	istics of MOSFET, short channel and Narrow width effects eling for low frequency and High frequency, high-k gate diele and drain resistance.	s, MOSFE	T scaling,
Small signa	l mod ource	istics of MOSFET, short channel and Narrow width effects eling for low frequency and High frequency, high-k gate diele	s, MOSFE	T scaling, ra-shallow
Small signa junctions, so UNIT-III Low field n characteristic transconduct	nobility cs, sub	istics of MOSFET, short channel and Narrow width effects eling for low frequency and High frequency, high-k gate diele and drain resistance. MOBILITY MODELS AND MOS	s, MOSFE ectrics, ult	T scaling, ra-shallow 10 hours off current ductance and
Small signa junctions, so UNIT-III Low field n characteristic transconduct	I mode ource a large of the lar	istics of MOSFET, short channel and Narrow width effects eling for low frequency and High frequency, high-k gate dielerand drain resistance. MOBILITY MODELS AND MOS PERFORMANCE PARAMETERS y, high field mobility, mobility various models, on current characteristics threshold swing, effect of interface states on sub threshold swing, effect of source bias and body bias on threshold voltage and device	s, MOSFE ectrics, ult	T scaling, ra-shallow 10 hours off curren ductance and Large signal
Small signal junctions, so UNIT-III Low field in characteristic transconduct Modeling, sn UNIT-IV Multiple gate FD SOI devi	nobility nobility s, sub- ance, e mall sig	ristics of MOSFET, short channel and Narrow width effects eling for low frequency and High frequency, high-k gate dielerand drain resistance. MOBILITY MODELS AND MOS PERFORMANCE PARAMETERS y, high field mobility, mobility various models, on current charthreshold swing, effect of interface states on sub threshold swing, effect of source bias and body bias on threshold voltage and device gnal model for low, medium and high frequencies. THE SOI MOSFET MOSFETs: double gate, FINFET, comparison of capacitances with mort channel effects, current-voltage characteristics: Lim &Fossum and high field effects: Kink effect and Hot-carrier degradation, Floating for the source of the source	racteristics drain concoperation, bulk MOS model and	T scaling, ra-shallow 10 hours off current ductance and Large signal 6 hours FET, PD and C-∞ model
Small signa junctions, so UNIT-III Low field in characteristic transconduct. Modeling, sn UNIT-IV Multiple gate FD SOI devimpact ionizations.	nobilities, subance, e mall signatures, slation a self-he	ristics of MOSFET, short channel and Narrow width effects eling for low frequency and High frequency, high-k gate dielerand drain resistance. MOBILITY MODELS AND MOS PERFORMANCE PARAMETERS y, high field mobility, mobility various models, on current charthreshold swing, effect of interface states on sub threshold swing, effect of source bias and body bias on threshold voltage and device gnal model for low, medium and high frequencies. THE SOI MOSFET MOSFETs: double gate, FINFET, comparison of capacitances with mort channel effects, current-voltage characteristics: Lim &Fossum and high field effects: Kink effect and Hot-carrier degradation, Floating for the source of the source	racteristics drain concoperation, bulk MOS model and	T scaling, ra-shallow 10 hours off curren ductance and Large signa 6 hours FET, PD and C-∞ model and parasition
Small signations, so UNIT-III Low field in characteristic transconduct Modeling, sn UNIT-IV Multiple gate FD SOI devimpact ionizaries BJT effects, su UNIT-V	nobility es, sub- ance, e mall sig e SOI I ices, sl ation a self-he	istics of MOSFET, short channel and Narrow width effects eling for low frequency and High frequency, high-k gate dielected and drain resistance. MOBILITY MODELS AND MOS PERFORMANCE PARAMETERS y, high field mobility, mobility various models, on current chat threshold swing, effect of interface states on sub threshold swing, effect of source bias and body bias on threshold voltage and device gnal model for low, medium and high frequencies. THE SOI MOSFET MOSFETs: double gate, FINFET, comparison of capacitances with nort channel effects, current-voltage characteristics: Lim &Fossum and high field effects: Kink effect and Hot-carrier degradation, Floating. SPICE MODELS FOR SEMICONDUCTOR	racteristics drain concoperation, bulk MOS model and ating body	T scaling, ra-shallow 10 hours off currenductance and Large signa 6 hours FET, PD and C-∞ model and parasition
Small signal junctions, so UNIT-III Low field in characteristic transconduct Modeling, sn UNIT-IV Multiple gate FD SOI deviimpact ionize BJT effects, su UNIT-V SPICE Mode parameters;	nobility nobility s, sub ance, e mall sig e SOI l ices, sl ation a self-he	ristics of MOSFET, short channel and Narrow width effects eling for low frequency and High frequency, high-k gate dielerand drain resistance. MOBILITY MODELS AND MOS PERFORMANCE PARAMETERS y, high field mobility, mobility various models, on current charthreshold swing, effect of interface states on sub threshold swing, effect of source bias and body bias on threshold voltage and device gnal model for low, medium and high frequencies. THE SOI MOSFET MOSFETs: double gate, FINFET, comparison of capacitances with nort channel effects, current-voltage characteristics: Lim &Fossum and high field effects: Kink effect and Hot-carrier degradation, Floating. SPICE MODELS FOR SEMICONDUCTOR DEVICES	racteristics drain concoperation, bulk MOS model and ating body 3 model,	T scaling, ra-shallow 10 hours off currenductance and Large signa 6 hours FET, PD and C-∞ model and parasition 8 hours Model
Small signal junctions, so UNIT-III Low field in characteristic transconduct Modeling, sn UNIT-IV Multiple gate FD SOI deviimpact ionize BJT effects, su UNIT-V SPICE Mode parameters; Course O	nobility nobility ses, sub ance, e mall sig e SOI l ices, sl ation a self-he lels for	ristics of MOSFET, short channel and Narrow width effects eling for low frequency and High frequency, high-k gate dielected and drain resistance. MOBILITY MODELS AND MOS PERFORMANCE PARAMETERS y, high field mobility, mobility various models, on current chan threshold swing, effect of interface states on sub threshold swing, effect of source bias and body bias on threshold voltage and device gnal model for low, medium and high frequencies. THE SOI MOSFET MOSFETs: double gate, FINFET, comparison of capacitances with mort channel effects, current-voltage characteristics: Lim &Fossum and high field effects: Kink effect and Hot-carrier degradation, Floating. SPICE MODELS FOR SEMICONDUCTOR DEVICES T Semiconductor Devices: MOSFET Level 1, Level 2 and level	racteristics drain concoperation, bulk MOS model and ating body 3 model,	T scaling, ra-shallow 10 hours off currenductance and Large signa 6 hours FET, PD and C-∞ model and parasition 8 hours Model

CO 3	Explain and analyse the Mobility models, MOS Performance parameters and its	
	frequency limitations.	
CO 4	Explain and analyse SOI MOSFET.	
CO 5	Explain and analyse SPICE Models for Semiconductor Devices.	

Text Books

- 1. E.H. Nicollian, J. R. Brews, Metal Oxide Semiconductor Physics and Technology, John Wiley and Sons.
- 2. Nandita Das Guptha, Amitava Das Guptha, Semiconductor Devices Modeling and Technology, Prentice Hall India
- 3. Jean- PierrieColinge, Silicon-on-insulator Technology: Materials to VLSI, Kluwer Academic publishers group.

Reference Books

- 1. P. Colinge, "FinFETs and Other Multi-Gate Transistors", Springer. 2009
- 2. Yannis Tsividis, Operation and Modeling of the MOS transistor, Oxford University Press.

Video Lecture Links:

Unit I:

https://www.youtube.com/watch?v=KohWxkovp0k

https://www.youtube.com/watch?v=CT6olzelSKQ

https://ocw.tudelft.nl/course-lectures/semiconductor-junction/

Unit II:

https://www.youtube.com/watch?v=0C4uxtS-tlQ

https://www.youtube.com/watch?v=XcDeh98ppXk

https://www.youtube.com/watch?v=uHTyw4GGnRo

https://www.youtube.com/watch?v=xSh9PZZPpOc

Unit III:

https://www.youtube.com/watch?v=4m49vM0Ryt8

https://www.youtube.com/watch?v=xgYdLvWcvms

https://www.youtube.com/watch?v=IrbGAgrcvic

Unit IV:

https://www.youtube.com/watch?v=WWjldCmRteg

https://www.youtube.com/watch?v=syRQTHF88eQ

https://nptel.ac.in/courses/113/104/113104012/

https://www.youtube.com/watch?v=vS3S1KfNLhE

Unit V:

https://nptel.ac.in/courses/117/106/117106033/

https://www.digimat.in/nptel/courses/video/108107129/L04.html

https://www.digimat.in/nptel/courses/video/117105147/L01.html

https://www.coursera.org/lecture/averagedswitchmodelingandsimulation/spice-simulation-

example-pJ99m

NPTEL course video link:

https://nptel.ac.in/courses/117/106/117106033/

	M. TECH FIRST YEAR		
Course Code	AMTVL0113	LTP	Credit
Course Title	Analog IC Design	3 0 0	03
Course Object			00
1	To develop the ability to design and analyze MOS based		
1	Analog VLSI circuits.		
2	To analyze the performance of single stage amplifier		
3	To develop the skills to design Differential Amplifier		
	circuits for a given specification.		
4	Analyze the frequency response of the different		
_	configurations of an amplifier		
5	To provide the knowledge of operational amplifier &		
D	feedback topologies.		
Pre-requisites	S: Basic electronics devices, Semiconductor & Amplifiers		
ı	Course Contents / Syllabus		
UNIT-I	BASIC MOS DEVICE PHYSICS		hours
	ations, MOSFET as a Switch, MOS I/V Characteristics, Se		
	dels, MOS Device Capacitances, NMOS versus PMOS Dev	vices, Lon	g-Channel
versus Short-Char			0.1
UNIT-II	SINGLE-STAGE AMPLIFIERS		8 hours
	Common-Source Stage, Common-Source Stage with Resistive 1		
	Load, CS Stage with Current-Source Load, Source Follower, C	Common-C	date Stage,
Cascode Stage, Fo	DIFFERENTIAL AMPLIFIERS		0 1
UNIT-III		26.1	8 hours
	d Differential Operation, Basic Differential Pair, Commo		
	vith MOS Loads, Gilbert Cell, Passive and Active Current Mi Current Mirrors, Active Current Mirrors, Common-Mode Prope		sic Current
UNIT-IV	FREQUENCY RESPONSE OF AMPLIFIERS		8 hours
0 - 1 1	ations, Miller Effect, Association of Poles with Nodes, Con	nmon Sou	
	Common-Gate Stage, Cascode Stage, Differential Pair, Noise		
	gies, Effect of Loading, Effect of Feedback on Noise	III DIIICIO	iniai i ans
UNIT-V	OPERATIONAL AMPLIFIERS		8 hours
	ations, Performance Parameters, One-Stage Op Amps, Two-Sta	age On Ai	
	arison, Common-Mode Feedback. Input Range Limitations		
Supply Rejection.	, 1 8	,	,
Course Outco	ome: After successful completion of this course studen	its will b	e able to
CO 1	Draw the equivalent circuits of MOS based Analog VLSI ar	nd	
	analyse their performance.		
CO 2	Design analog VLSI circuits for a given specification.		
CO 3	Analyse the frequency response of the different configuration	ns	
CO 4	of an amplifier.		
CO 4	Analyse the feedback topologies involved in the amplifier design.		
CO 5	Appreciate the design features of the differential amplifiers.		

- 1. Razavi, "Design of Analog CMOS Integrated Circuits", 2nd Edition, McGraw Hill Edition 2016.
- 2. Paul. R.Gray&Robert G. Meyer, "Analysis and Design of Analog Integrated Circuits", Wiley, 5th Edition, 2009.
- 3. R. Gregorian and Temes, "Analog MOS Intgrated Circuits for Signal Processing", Wiley Publications

- 1. Ken Martin, "Analog Integrated Circuit Design", Wiley Publications.
- 2. Sedra and Smith, "Microelectronic Circuits", Oxford Publications.
- 3. B.Razavi, "Fundamentals of Microelectronics", Wiley Publications

M. TECH FIRST YEAR							
Course Code	AMTVL0114	T	P	Credit			
Course Title		0		03			
	Course Objective:						
1	To analyze the basic stages of manufacturing and cryst	al g	rowt	h.			
2	To evaluate the process of wafer preparation and oxida						
3	To analyze the lithography and etching process						
4	To explain process of diffusion and ion implantation.						
5	To learn the basic process involved in metallization and	d pa	ckag	ging			
Pre-requisites:	Basics of semiconductors and their properties.						
	Course Contents / Syllabus						
UNIT-I	OVERVIEW OF SEMICONDUCTOR INDUSTRY	7	8	hours			
Semiconductor m	conductor industry, Process and Product Trends, Stages naterial properties, Crystal growth, Basic wafer fabrilicon Preparation, Czochralski (CZ) method, Float zone,	icati	on (operations,			
UNIT-II	WAFER FABRICATION			8 hours			
	reparation, Wafer Terminology , Basic Wafer-Fabric			•			
	rning, Doping, Heat treatments, Circuit design, ma			xample of			
	ss, Oxidation: Dry and wet oxidation, Clean room Constr	ructi	on.				
UNIT-III	LITHOGRAPHY AND ETCHING			8 hours			
	ng process, Lithography: Optical Lithography, Electron Chemical Etching, Dry etching Wet etching.	bea	m li	thography,			
UNIT-IV	DOPING AND DEPOSITION			8 hours			
Implantation: Ion		CVD	bas	sics, CVD			
UNIT-V	METALLIZATION AND PACAKAGING			8 hours			
Deposition, Vacuu Types, Packaging							
Course Outcor	ne: After successful completion of this course studer	nts v	vill 1	be able to			
CO 1	Analyze the basic stages of manufacturing and crystal a	grov	vth.				
CO 2	Evaluate the process of wafer preparation and oxidation	n.					
CO 3	Analyze the lithography and etching process.						
CO 4	Explain the process of diffusion and ion implantation.						
CO 5	Learn the basic process involved in metallization and p	ack	agin	g			
Text books							
1. Peter Van Zant	, Microchip fabrication, McGraw Hill, 1997.						

2. S.M. Sze, VLSI technology, McGraw-Hill Book company, NY, 1988

- 1. Wani-Kai Chen (editor), The VLSI Hand book, CRI/IEEE press, 2000
- 2. C.Y. Chang and S.M. Sze, ULSI technology, McGraw Hill, 2000
- 3. S.K. Ghandhi, "VLSI Fabrication Principles", Willy-India Pvt. Ltd, 2008.
- 4. J. D. Plummer, M. D. Deal and Peter B. Griffin, "Silicon VLSI Technology: Fundamentals, Practice and Modeling", Pearson Education Publication, 2009

	M. TECH FIRST YEAR		
Course Code	AMTVL0115	LT P	Credit
Course Title	Clean Room Technology And Maintenance	300	03
Course Objectiv	ve:		
1	Study and explain cleanroom standards and cleanrooms.	ancillary	
2	Knowledge about clean room fabrication environment.		
3	Identify the various filtration mechanisms.		
4	Categorize cleanroom testing and monitoring system.		
5	Analyze air quantities, pressure differences and clean r disciplines.	room	
Pre-requisites:	Basics of IC Technology		
	Course Contents / Syllabus		
UNIT-I	INTRODUCTION TO CLEAN ROOM TECHNOI	LOGY	8 hours
Clean room stan	nroom Classification Standards, Unidirectional air flow dards, Federal Standards 209 ,ISO standard 146 maceutical, cleanrooms)		
UNIT-II	CLEAN ROOM ENVIRONMENT		8 hours
UNIT-III	FILTRATION MECHANISM		8 hours
	r filtration, Particle removal mechanisms, testing of high	efficiency	
UNIT-IV	TESTING & MONITORING SYSTEM		8 hours
	and Monitoring, Principles of cleanroom testing, Testin state, Monitoring of cleanroom.	ng in relat	on to room
UNIT-V	CLEAN ROOM STANDARD PARAMETERS		8 hours
	ir Quantities and Pressure Differences, Air movement on containment leak testing.	control, Re	ecovery test
Course Outcom	e: After successful completion of this course studen	ts will be a	able to
CO 1	Specify cleanroom standards and ancillary cleanrooms		
CO 2	Explain about clean room fabrication environment.		
CO 3	Identify the surface finishes and filtration mechanisms.		
CO 4	Categorize cleanroom testing and monitoring system.		
CO 5	Analyze air quantities, pressure differences and clean r disciplines.	room	
Text books			
1. William W	hite, Cleanroom Technology: Fundamentals of De	esign, Tes	ting and

Operation, 2nd Edition, Wiley, 2010.

	atts Ramstorp, Introduction to Contamination Control and Cleanroom Technology, Tiley, 2008.			
Referen	Reference Books			
1. W	Vani-Kai Chen (editor), The VLSI Hand book, CRI/IEEE press, 2000			
Link:				
Unit 1	https://www.youtube.com/watch?v=8uGZMyjFugg			
Unit 2	https://www.youtube.com/watch?v=YAouXIS_FSU			
Unit 3	https://www.youtube.com/watch?v=wSSfOqEQClc			
Unit 4	https://www.youtube.com/watch?v=aBIxPo0p7dc			
Unit 5	https://www.youtube.com/watch?v=lHmHYWdH8Ug			

	M. TECH FIRST YEAR	
Course Code	AMTVL0116 L T P	Credit
Course Title	ULSI Technology 3 0 0	03
Course Objectiv	ve:	1
1	To study the basics of chip fabrication and clean room.	
2	To learn the ion implantation and variousOxidation technologies.	
3	To study the classification of lithographic techniques.	
4	To identify various metallization schemes.	
5	To explain the concept of Memories.	
Pre-requisites:	Microelectronics	
	Course Contents / Syllabus	
UNIT-I	CLEAN ROOM AND WAFER PREPARATION	8 hours
wet chemical etcl	LSI technology: clean room and safety requirements, Wafer cleaning techniques, Microelectronics and microscopy, ULSI proce of for construction analysis, TEM sample preparation techniques.	
UNIT-II	IMPURITY INCORPORATION	9 hours
	SI; Characterization of oxide films; high K and low K dielectrics for	TIT OI
	T THE COLUMN OF	1
UNIT-III Photolithography to	LITHOGRAPHIC TECHNIQUES	9 hours
Photolithography to Chemical Vapour dioxide, silicon nit implantation and Metallization and in	deposition techniques: CVD techniques for deposition of polystride and metal films; epitaxial growth of silicon; modelling and to substrate defects, Dielectrics and isolation, Silicides, polycide interconnects.	9 hours silicon, silicon echnology. Ion and salicide,
Photolithography to Chemical Vapour dioxide, silicon nit implantation and Metallization and in UNIT-IV	deposition techniques: CVD techniques for deposition of polystride and metal films; epitaxial growth of silicon; modelling and to substrate defects, Dielectrics and isolation, Silicides, polycide interconnects. METALLIZATION TECHNIQUES	9 hours silicon, silicon echnology. Ion and salicide,
Photolithography to Chemical Vapour dioxide, silicon nit implantation and Metallization and it UNIT-IV Evaporation and Metallization scheme	deposition techniques: CVD techniques for deposition of polystride and metal films; epitaxial growth of silicon; modelling and to substrate defects, Dielectrics and isolation, Silicides, polycide interconnects.	9 hours silicon, silicon echnology. Ion and salicide, 8 hours ets; multilevel in under bump
Photolithography to Chemical Vapour dioxide, silicon nit implantation and Metallization and in UNIT-IV Evaporation and Metallization schemetallization and	deposition techniques: CVD techniques for deposition of polystride and metal films; epitaxial growth of silicon; modelling and to substrate defects, Dielectrics and isolation, Silicides, polycide interconnects. METALLIZATION TECHNIQUES sputtering techniques. Failure mechanisms in metal interconnectes. TEM in failure analysis, Novel devices and materials, TEM	9 hours silicon, silicon echnology. Ion and salicide, 8 hours ets; multilevel in under bump
Photolithography to Chemical Vapour dioxide, silicon nit implantation and Metallization and in UNIT-IV Evaporation and Metallization schemetallization and microelectronics. UNIT-V DRAM cell with p	deposition techniques: CVD techniques for deposition of polystride and metal films; epitaxial growth of silicon; modelling and to substrate defects, Dielectrics and isolation, Silicides, polycide interconnects. METALLIZATION TECHNIQUES	9 hours silicon, silicon echnology. Ion and salicide, 8 hours ets; multilevel in under bump tion TEM in 6 hours
Photolithography to Chemical Vapour dioxide, silicon nit implantation and Metallization and in UNIT-IV Evaporation and Metallization schemetallization and microelectronics. UNIT-V DRAM cell with p III: DRAM cell with	deposition techniques: CVD techniques for deposition of polystride and metal films; epitaxial growth of silicon; modelling and to substrate defects, Dielectrics and isolation, Silicides, polycide interconnects. METALLIZATION TECHNIQUES	9 hours silicon, silicon echnology. Ion and salicide, 8 hours ets; multilevel in under bump tion TEM in 6 hours , ULSI devices
Photolithography to Chemical Vapour dioxide, silicon nit implantation and Metallization and in UNIT-IV Evaporation and Metallization schemetallization and microelectronics. UNIT-V DRAM cell with p III: DRAM cell with	deposition techniques: CVD techniques for deposition of polystride and metal films; epitaxial growth of silicon; modelling and to substrate defects, Dielectrics and isolation, Silicides, polycide nterconnects. METALLIZATION TECHNIQUES sputtering techniques. Failure mechanisms in metal interconnemes. TEM in failure analysis, Novel devices and materials, TEM advanced electronics packaging technologies, High – resolution of polycide necessary. ULSI DEVICES lanar capacitor, ULSI devices II: DRAM cell with stacked capacitor the trench capacitor, ULSI devices IV: SRAM.	9 hours silicon, silicon echnology. Ion and salicide, 8 hours ets; multilevel in under bump tion TEM in 6 hours , ULSI devices
Photolithography to Chemical Vapour dioxide, silicon nit implantation and Metallization and in UNIT-IV Evaporation and Metallization schemetallization and microelectronics. UNIT-V DRAM cell with p III: DRAM cell with	deposition techniques: CVD techniques for deposition of polystride and metal films; epitaxial growth of silicon; modelling and to substrate defects, Dielectrics and isolation, Silicides, polycide nterconnects. METALLIZATION TECHNIQUES	9 hours silicon, silicon echnology. Ion and salicide, 8 hours ets; multilevel in under bump tion TEM in 6 hours , ULSI devices

CO 4	Explain and analyze metallization schemes.
CO 5	Design semiconductor memories.
Text books	
1. S.M. Sze(2nd Ed	ition)"VLSI Technology", McGraw Hill Companies Inc.
2. Chih-Hang Tung	, George T.T. Sheng, Chih-Yuan Lu, ULSI Semiconductor Process
Technology Atlas, J	ohn Wiley & Sons, 2003.

Reference Books

1. Stephena, Campbell, "The Science and Engineering of Microelectronic Fabrication", Second Edition, Oxford University Press.

3. C.Y. Chang and S.M. Sze (Ed), "ULSI Technology", 2000, McGraw Hill Companies Inc.

2. James D. Plummer, Michael D. Deal, "Silicon VLSI Technology" Pearson Education Reading.

	M. TECH FIRST YEAR		
Course Code	AMTVL0201	LT P	Credit
Course Title	Digital Design using FPGA and CPLD	300	03
Course Objecti	ve:		
1	To study finite state machines and its realization.		
2	To study asynchronous Sequentialmachine.		
3	To learn Designing of Digital logic using PLD.		
4	To get knowledge of different FPGA series.		
5	To study different CPLD series.		
Pre-requisites:	Basics of CMOS and Fabrication.		
	Course Contents / Syllabus		
UNIT-I	FINITE STATE MACHINE (FSM)		nours
from verbal descri State Machine, Inti	gn Strategies, Mealy & Moore model, Realization of State Diption, Minimization of State Table from completely & In roduction to Algorithmic State Machine.		y specified
UNIT-II	ASYNCHRONOUS SEQUENTIAL CIRCUIT		8 hours
machine, Races & UNIT-III	PROGRAMMABLE LOGIC DEVICES (PLD)		8 hours
· ·	ecture, Features & Digital Design of ROM, EPROM, EEPROM Design of a keypad scanner using PLD.	I, Flash M	emory,
UNIT-IV	FIELD PROGRAMMABLE GATE ARRAY (FPGA)		8 hours
Xilinx FPGA XC4	ting architecture, Design flow, Technology Mapping for FPG 4000, Comparative Study of Xilinx (ZU11EG) & Intel (Strateference to cortex A53.		X650 series
UNIT-V	COMPLEX PROGRAMMABLE LOGIC DEVICES (CPLD)		8 hours
(Mach 1 to 5), Cy Speed performance	x 5000/7000 series and Altera FLEX logic- 10000 series CI press FLASH 370 Device technology, Lattice plsi architect and system programmability.	tures – 30	
Course Outcon	ne: After completion of this course students will be able t	0	
CO 1	Realize finite state machines.		
CO 2	Formulate asynchronous Sequentialmachine.		
CO 3	Design Digital logic using PLD.		
CO 4	Explain different FPGA series.		
CO 5	Explain different CPLD series.		

- 1. P. K. Chan& S. Mourad, Digital Design using Field Programmable Gate Array, Prentice Hall.
- 2. Charles H Roth, Jr., "Digital Systems Design Using VHDL", PWS, 1998.
- 3. S. Trimberger, Edr., Field Programmable Gate Array Technology, Kluwer Academic Pub.

- 1. J. Old Field, R. Dorf, Field Programmable Gate Arrays, John Wiley& Sons, Newyork.
- 2. S.Brown, R.Francis, J.Rose, Z.Vransic, Field Programmable GateArray, Kluwer Pub.
- 3. Richard FJinder, "Engineering Digital Design," Academic press

M. TECH FIRST YEAR								
Course Code	AMTVL0202 LT P	Credit						
Course Title	Low Power VLSI Design 3 0 0							
Course Objectiv	Course Objective:							
1	To provide the knowledge of Low Power VLSI Chips and different losses associated with the CMOS Devices							
2	To provide the knowledge of Power estimation Simulation Power analysis and Probabilistic power analysis of Design							
3	To provide the knowledge of circuit level and Logic level design.							
4	To provide the knowledge of Low Power Architecture and system							
5	To provide the basic knowledge of Low Power Clock Distribution							
	Algorithm & Architectural Level Methodologies							
Pre-requisites:	CMOS VLSI Design, Digital logic Design.							
•	Course Contents / Syllabus							
UNIT-I	INTRODUCTION & DEVICE AND TECHNOLOGY	8 hours						
	IMPACT ON LOW POWER	o nours						
Introduction: Need	ds for Low Power VLSI Chips, Sources of power dissipation on dig	ital integrated						
	ow power approaches, Physics of power dissipation in CMOS Device	_						
Device and techno	logy impact on low power: Dynamic dissipation on low power, Tra	ansistor sizing						
	ness, Impact of technology Scaling, Technology & Device innovatio							
		**						
UNIT-II	POWER ESTIMATION SIMULATION POWER							
UNIT-II	POWER ESTIMATION SIMULATION POWER ANALYSIS&PROBABILISTIC POWER ANALYSIS							
Power estimation	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level	8 hours						
Power estimation simulation, Capacit	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level ive Power Estimation, Static State Power, Gate level Capacitance Estimation, Static State Power, Gate Inc.	8 hours logic						
Power estimation simulation, Capacit Architecture Level	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estanalysis, Data Correlation Analysis in DSP systems. Monte Carlo simulations are supported by the control of the contro	8 hours logic stimation, mulation.						
Power estimation simulation, Capacit Architecture Level Probabilistic power	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estimation, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis: - Random Logic Signals. Probability & frequency, Proba	8 hours logic stimation, mulation.						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Technology	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estanalysis, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis: - Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy.	8 hours logic stimation, mulation. bilistic						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Tecture UNIT-III	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estimation, Data Correlation Analysis in DSP systems. Monte Carlo siter analysis: - Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN	8 hours logic stimation, mulation. bilistic 8 hours						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Teat UNIT-III Circuit level: Power	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estanalysis, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis:- Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN ver Consumption in circuit level, Flip Flop & Latches design, High	8 hours logic stimation, mulation. bilistic 8 hours						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Ted UNIT-III Circuit level: Power node, Low power designation.	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estanalysis, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis:- Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN Ter Consumption in circuit level, Flip Flop & Latches design, High rigital cell library	8 hours logic stimation, mulation. bilistic 8 hours Capacitance						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Ted UNIT-III Circuit level: Pownode, Low power d Logic Level: Gate	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estanalysis, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis:- Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN ver Consumption in circuit level, Flip Flop & Latches design, High	8 hours logic stimation, mulation. bilistic 8 hours Capacitance						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Teat UNIT-III Circuit level: Pownode, Low power d Logic Level: Gate computation logic	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estimation, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis:- Random Logic Signals. Probability & frequency, Probability & frequency, Probability & Signal Entropy. LOW POWER DESIGN Ter Consumption in circuit level, Flip Flop & Latches design, High igital cell library Reorganisation, Signal gating, Logic encoding, state machine of	8 hours logic stimation, mulation. bilistic 8 hours Capacitance						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Tea UNIT-III Circuit level: Pownode, Low power de Logic Level: Gate computation logic UNIT-IV	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estimation, Static State Power, Gate level Capacitance Estimation, DSP systems. Monte Carlo sincer analysis: - Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN Ter Consumption in circuit level, Flip Flop & Latches design, High igital cell library Reorganisation, Signal gating, Logic encoding, state machine of the LOW POWER ARCHITECTURE AND SYSTEM	8 hours logic stimation, mulation. bilistic 8 hours a Capacitance encoding, Pre 8 hours						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Ted UNIT-III Circuit level: Power node, Low power d Logic Level: Gate computation logic UNIT-IV Power & Perform	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estanalysis, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis:- Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN Ter Consumption in circuit level, Flip Flop & Latches design, High rigital cell library Reorganisation, Signal gating, Logic encoding, state machine of the Company	8 hours logic stimation, mulation. bilistic 8 hours a Capacitance encoding, Pre 8 hours hitecture with						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Teat UNIT-III Circuit level: Power and Logic Level: Gate computation logic UNIT-IV Power & Perform Voltage Reduction	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estimation, Static State Power, Gate level Capacitance Estimation, DSP systems. Monte Carlo sincer analysis: - Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN Ter Consumption in circuit level, Flip Flop & Latches design, High igital cell library Reorganisation, Signal gating, Logic encoding, state machine of the LOW POWER ARCHITECTURE AND SYSTEM	8 hours logic stimation, mulation. bilistic 8 hours a Capacitance encoding, Pre 8 hours attecture with						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Teat UNIT-III Circuit level: Power description logic Level: Gate computation logic UNIT-IV Power & Perform Voltage Reduction Memory Design	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estimation, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis: - Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN Therefore Consumption in circuit level, Flip Flop & Latches design, High igital cell library Reorganisation, Signal gating, Logic encoding, state machine of the LOW POWER ARCHITECTURE AND SYSTEM ance Management, Switching Activity Reduction, Parallel Arch, Flow graph Transformation, Low Power Arithmetic Component	8 hours logic stimation, mulation. bilistic 8 hours a Capacitance encoding, Pre 8 hours sitecture with Low Power						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Teat UNIT-III Circuit level: Power and Logic Level: Gate computation logic UNIT-IV Power & Perform Voltage Reduction	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estanalysis, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis:- Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN Ter Consumption in circuit level, Flip Flop & Latches design, High rigital cell library Reorganisation, Signal gating, Logic encoding, state machine of the Company	8 hours logic stimation, mulation. bilistic 8 hours a Capacitance encoding, Pre 8 hours attecture with						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Teat UNIT-III Circuit level: Pownode, Low power decomputation logic UNIT-IV Power & Perform Voltage Reduction Memory Design UNIT-V Low Power Clock Low Capacita Level Level Level Level Reduction Memory Design	Simulation Power analysis: - SPICE circuit simulators, Gate level ive Power Estimation, Static State Power, Gate level Capacitance Estanalysis, Data Correlation Analysis in DSP systems. Monte Carlo sizer analysis: - Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN The Consumption in circuit level, Flip Flop & Latches design, High igital cell library Reorganisation, Signal gating, Logic encoding, state machine of the LOW POWER ARCHITECTURE AND SYSTEM ance Management, Switching Activity Reduction, Parallel Arch, Flow graph Transformation, Low Power Arithmetic Component LOW POWER CLOCK DISTRIBUTION & ALGORITHM & ARCHITECTURAL LEVEL METHODOLOGIES Ek Distribution: -Power dissipation in clock distribution, sing	8 hours logic stimation, mulation. bilistic 8 hours n Capacitance encoding, Pre 8 hours sitecture with n Low Power 8 hours						
Power estimation simulation, Capacit Architecture Level Probabilistic power Power Analysis Teat UNIT-III Circuit level: Power of Logic Level: Gate computation logic UNIT-IV Power & Perform Voltage Reduction Memory Design UNIT-V Low Power Clock distributed buffers,	ANALYSIS&PROBABILISTIC POWER ANALYSIS Simulation Power analysis: - SPICE circuit simulators, Gate level rive Power Estimation, Static State Power, Gate level Capacitance Estimations, Data Correlation Analysis in DSP systems. Monte Carlo simple analysis: - Random Logic Signals. Probability & frequency, Probachniques, Signal Entropy. LOW POWER DESIGN For Consumption in circuit level, Flip Flop & Latches design, High rigital cell library Reorganisation, Signal gating, Logic encoding, state machine of the Rand Power Architecture and System ance Management, Switching Activity Reduction, Parallel Arch, Flow graph Transformation, Low Power Arithmetic Component LOW POWER CLOCK DISTRIBUTION & ALGORITHM & ARCHITECTURAL LEVEL METHODOLOGIES	8 hours logic stimation, mulation. bilistic 8 hours n Capacitance encoding, Pre 8 hours sitecture with y, Low Power 8 hours le driver Vs etwork						

analysis and optimization, Architectural level estimation and synthesis

Course Outco	ome: After successful completion of this course students will be able to	
CO 1	Identify different losses associated with the CMOS Devices.	
CO 2	Explain the concept of Power estimation Simulation Power analysis and Probabilistic Power analysis of Design.	
CO 3	Identify circuit and logic level low power design.	
CO 4	Analyze the Low Power Architecture and system.	
CO 5	Explain Low Power Clock Distribution Algorithm.	
Text books		
1. Gary K. Y	Yeap, Practical Low Power Digital VLSI Design, KAP 2007	
2. Rabaey, I	Pedram , "Low power design methodologies" Kluwer Academic, 1997	
Reference Bo	oks	
1. Kaushik l	Roy, Sharat Prasad, "Low-Power CMOS VLSI Circuit" Wiley 2000	

			M. TE	CH FII	RST YI	EAR				
Course C	ode	AMTVL0	251						LTP	Credit
Course Title Digital Design using FPGA and CPLD Lab							0 0 4	02		
Pre-requi	sites: Ba	sics Knowledg	ge of Digital E	Electronic	cs & Digi	ital Syste	em Design	n		
Sr. No.	List of Experiment									
1	Demon	stration of FP	GA and CPLD	Boards.						
2			the Boolean E					LD.		
3	Design	& Implement	Full adder and	d Full Su	ubtractor	on CPLI).			
4.			(i) 2-bit compa					8x1 Mu	ıltiplexer	on CPLD.
5	Design	& Implement	S-R, J-K, D ar	ınd T Flip	p Flops o	n FPGA	•			
6	Design FPGA.		t (i) Universal	l shift re	egister (ii	i) 4- bit	UP-DOV	VN Syı	nchronous	Counter on
7	Design	& Implement	the (i) 4-bit A	LU (ii) 8	8- bit SR.	AM on F	PGA.			
8	Design	& Implement	7- Segment D	Display D	Priver circ	cuit using	g CPLD.			
9	Design	& Implement	Sequence Dete	tector Cir	rcuit to d	etect giv	en sequer	nce 101	01010 on	FPGA.
10	Modell	ing and Imple	mentation of U	UART on	n FPGA.					
Lab Cou	rse Outo	come: After	completion of	f this cou	urse stud	lents wil	l be able	to		
CO 1	Design	& Implement	the Combinati	tional Lo	gic Circu	its on C	PLD.			
CO 2	Design	Design & Implement the Sequential Logic Circuits on CPLD.								
CO 3	Design	Design & Implement the Memories on FPGA.								
CO 4	Design	& Implement	UART on FPC	GA.						
Link:										
1	https://	www.youtube.	.com/watch?v=	=9mpRF	F6bAY1g					
2	https://www.youtube.com/watch?v=EGDHXynlXMk									
3	https://www.youtube.com/watch?v=H2GyAIYwZbw									
4	https://	www.youtube.	.com/watch?v=	=WKZgI	K3BKDI	0				
5		www.youtube. index=6	.com/watch?v=	=s3Dk4C	CEfNg4&	zlist=PL.	J5C_6qd <i>A</i>	AvBEL	ELTSPgz	YkQg3Hgcl

M. TECH FIRST YEAR							
Course Code	AMTVL0252	LT P	Credit				
Course Title	Low Power VLSI Design Lab	004	02				
Software Tool: SOFTWARE TOOL: CADENCE – Tool Bundle Consisting of:							
1. ANALOG & MIXED SIGNAL DESIGN FRONT END TOOLS							
Virtuoso(R) Spectre(R) Simulator REL MMSIM 7.1							
	Virtuoso(R) Schematic Editor XL REL IC 6.1.0						
	ALOG BACK END TOOL						
	Virtuoso(R) Layout Suite XL REL IC 6.1.0						
	YSICAL DOMAIN						
	SOC Encounter - XL (aka Cadence (R) SOC Encount	er - GPS)					
Sr. No.	Name of Experiment	/					
1	I-V characteristics of long and short-channel MOSF	ET transisto	ors in CMOS				
	technology.						
2	The gate capacitance of an MOS transistor. (Gate Capa	citance v/s V	/GS).				
3	The impact of device variations on static CMOS invert		,				
4	The VTC of CMOS inverter as a function of supply vo		ostrate bias.				
•	The view of context in street as a summer of supply	211180 111111 2011	2242				
5	Dynamic power dissipation due to charging and discha	rging capaci	tances.				
6	Short-circuit currents during transients and impact of lo						
	circuit current in a CMOS inverter.	•					
7	The VTC of a two-input NAND & NOR data dependen	ncy.					
8	The variable-threshold CMOS inverter and Combination						
9	The low-power / low voltage D-Latch circuit.						
10	Low-power circuits						
	a. The Full Adder						
	b. The Binary Adder						
	c. The Multiplier						
	d. The Shifter.						
	e. The SRAM Cell						
	f. The DRAM Cell						
	itcome: After completion of this course students are						
CO 1	Study and analyze the various parameters of MOS Tran						
CO 2	Study and analyze the different parameters of CMO	S inverter fo	or low power				
	design.						
CO 3	Design and implement the combinational digital circuit	ts for low po	wer circuits.				
00.4	D : 1: 1 (4 (11: 1: 1: 1: 1: 1: 1: 1: 1: 1: 1: 1: 1:	1	• •,				
CO 4	Design and implement the sequential digital circuits fo	r low power	circuits.				
Link:							
Unit 1	https://www.youtube.com/watch?v=TFOO1JAll2Y						
	https://youtu.be/ruClwamT-R0						
Unit 2	https://www.analog.com/en/design-center/design-tools	s-and-calcula	tors/ltspice-				
	simulator.html						
	https://www.youtube.com/watch?v=OgO1gpXSUzU						

	https://nptel.ac.in/courses/111/106/111106134/
Unit 3	https://nptel.ac.in/courses/106/105/106105034/ https://www.youtube.com/watch?v=dqcfYTePRxQ https://www.youtube.com/watch?v=rEeqxozkdZ0
Unit 4	https://www.digimat.in/nptel/courses/video/106105034/L37.html
Unit 5	https://nptel.ac.in/courses/106/105/106105161/

	M. TECH FIRST YEAR		
Course Code	AMTVL0211	LTP	Credit
Course Title	VLSI Testing and Testability	3 0 0	03
Course Objectiv	e:		1
1	To provide an in-depth understanding of the importance principle of testing and verification of faults affecting V circuits.		
2	To provide the knowledge of the testing and testability combinational circuits.	of	
3	To provide the knowledge of the testing and testability of sequential circuits.	of	
4	To provide an in-depth understanding of the memory detesting methods.		
5	To provide the basic knowledge of Built in self-test (BIST Techniques.	ST)	
Pre-requisites:D	igital and analog IC fabrication.		
	Course Contents / Syllabus		
UNIT-I	INTRODUCTION TO VLSI TESTING AND FAUL MODELING	T	10 hours
testing, Functional v Testing, DC and AC	ciple of testing, Challenges in VLSI testing, Levels of ab s. Structural approach to testing, Complexity of the testing parametric tests ck at fault, fault equivalence, fault collapsing, fault domin	g problem	, Types of
UNIT-II	TESTING AND TESTABILITY OF COMBINATION CIRCUITS		8 hours
	ics: Test generation algorithms, Random test generation, its, Boolean difference, Path sensitization, D – algorithm, circuit design		
UNIT-III	TESTING AND TESTABILITY OF SEQUENTIAL CIRCUITS		8 hours
generation based on	l circuits as iterative combinational circuits, state table ve circuit structure, Sequential ATPG, s, scan path technique (scan design), partial scan, Boundar		test
UNIT-IV	MEMORY, DELAY, FAULT AND IDDQ TESTING	•	6 hours
•	rsign, RAM fault models, Test algorithms for RAM, Delang methods, Limitations of IDDQ testing	y faults, D	elay tests,
UNIT-V	BUILT IN SELF-TEST (BIST) TECHNIQUES		8 hours
testing, Output response	ST): Design rules, Exhaustive testing, Pseudo-random te onse analysis, Logic BIST architectures, Introduction to T	est compr	ession
Course Outcome	e: After successful completion of this course students	will be ab	ie to
CO 1	Apply the concepts in testing which can help them better yield in IC design	design a	

CO 2	Analyse the various test generation methods for combinational circuits.	
CO 3	Analyse the various test generation methods for sequential circuits.	
CO 4	Identify the design for testability methods for different memory circuits.	
CO 5	Recognize the BIST techniques for improving testability.	

- 1. An Introduction to Logic Circuit Testing Parag K. Lala, (Morgan & Claypool Publishers)
- 2. Essentials of Electronic Testing for Digital, Memory & Mixed Signal VLSI Circuits Michael L. Bushnell and Vishwani D. Agrawal, (Kluwar Academic Publishers 2000)
- 3. Digital System Testing and Testable Design M. Abramovici, M.Breuer, and A. Friedman (Jaico Publishing House)

- 1. Introduction to Formal Hardware Verification Thomas Kropf (Springer)
- 2. VLSI Test Principles and Architectures Design for Testability W.W. Wen (Morgan Kaufmann Publishers. 2006)
- 3. Digital Systems and Testable Design M.Abramovici, M.A. Breuer and A.D. Friedman (Jaico Publishing House)
- 4. Design Test for Digital IC's and Embedded Core Systems A.L. Crouch (Prentice Hall International)

Link:	
Unit 1	https://youtu.be/u_XLaTTzXaE
Unit 2	https://nptel.ac.in/courses/106/103/106103116/
Unit 3	https://nptel.ac.in/courses/106/103/106103116/
Unit 4	https://nptel.ac.in/courses/106/103/106103116/
Unit 5	https://nptel.ac.in/courses/106/103/106103116/

M. TECH FIRST YEAR							
Course Code	AMTVL0212	LTP	Credit				
Course Title	VLSI DSP Architectures	3 0 0	03				
Course Object	Course Objective:						
1	1 To explain basics of DSP processors and micro programming						
	approaches.						
2	To learn building a data path and control path.						
3	To outline pipelining and pipe lined data path.						
4	To analyzeA/D and D/A converters and DSP computations are computed to the converters and DSP computed to the converter to the	tional erro	ors.				
5	To identify thearchitectures for programmable	digital s	ignal				
	processing devices.						
Pre-requisites	: VLSI DSP Architecture						
	Course Contents / Syllabus						
UNIT-I	BASICS OF DSP PROCESSORS		8 hours				
	s of Instruction set architectures of DSP processo						
	aplementation of control part of the processor, CPU per	rformance	and its factors,				
evaluating perform							
UNIT-II	DATA PATH		9 hours				
	gic design conventions, building a data path, a simple i	mplement	ation scheme, a				
	mentation, simplifying control design.						
UNIT-III	PIPELINING		9 hours				
_	ipelining, a pipe lined data path, pipe lined control, data ach hazards, advanced pipelining: extracting more performance.		nd forwarding,				
UNIT-IV	CONVERSIONS		8 hours				
	for signals and coefficients in DSP systems, dynam	nic range					
	in DSP implementations, A/D conversion errors, and D						
D/A conversion	=	or comp.	stational Circis,				
UNIT-V	PROGRAMMABLE PROCESSORS		8 hours				
	architectures for programmable digital signal pro	ocessing					
	cures, DSP computational building blocks, bus arch						
	ess generation unit, speed issues, features for external in		S				
	me: After successful completion of this course stude		e able to				
CO 1	Identify basics of DSP processors and micro	program	ming				
	approaches.	1 - 0	9				
CO 2	Learn building a data path and control path.						
CO 3	Analyze pipelining and pipe lined data path.						
CO 4	CalculateA/D and D/A converters and DSP computati	onal errors	S.				
CO 5	Implement architectures for programmable digital sign devices.	gnal proce	ssing				
Text books			·				

1. D. A, Patterson and J.L Hennessy, "Computer Organization and Design: Hardware/ Software Interface", 4th Ed., Elsevier, 2011.

2. A. S Tannenbaum, "Structural Computer organization", 4th Ed., Prentice-Hall, 1999.

- 1. W. Wolf, "Modern VLSI Design: System on Silicon", 2nd Ed., Person Education,1998.
- 2. Keshab Parhi, "VLSI Digital Signal Processing system design and implementations", Wiley1999.

		M. TECH FIRST YEAR				
Cour	se Code	AMTVL0213	LT P	Credit		
Cour	se Title	Full Custom Design	300	03		
	se Objectiv	_				
1		l be familiar with the schematic fundamentals and layo	ut designs f	low.		
2						
	basic cells.	·	71			
3	Students wil	l be able to design interconnect layout and know specia	ıl electrical			
	requirements					
4		l be able to incorporate special design rules and step co	verage rule	S		
5	l .	l be able to learn various kind of CAD tools.				
Pre-r	equisites:B	asics of VLSI				
		Course Contents / Syllabus				
UNIT		INTRODUCTION		8 hours		
		matic fundamentals, Layout design, Introduction to		_		
-	-	and connectivity, Process design rules Significance o	f full custo	m IC design, layout		
	flows.	CDD CV. I VZDD DVVI DVVC DV O CVC				
UNIT		SPECIALIZED BUILDING BLOCKS		8 hours		
	-	es for specialized building blocks Standard cell librarie	s, Pad cells	and Laser fuse cells,		
		gnals and Interconnect routing.		0.1		
UNIT		LAYOUT DESIGNS		8 hours		
		design, Special electrical requirements, Layout design	techniques	to address electrical		
	teristics.	I AVOUT CONCIDED ATIONS		0.1		
UNIT		LAYOUT CONSIDERATIONS		8 hours		
-		ons due to process constraints Large metal via impler				
UNIT		, Latch-up and Guard rings, Constructing the pad ring, LAYOUT CAD TOOLS	Minimizing			
			- C 4 4	8 hours		
		tools for layout, Planning tools, Layout generation tool				
Cour	se Outcom	e: After successful completion of this course studen	its will be a	ble to		
CC	Design	gn layout with schematic.				
CC	Diffe	rentiate standard cells and other types of cells.				
CC	Do th	ne electrical connections and interconnect layout design	ıs.			
CC	O 4 Tack	le with the minimization of stress effects.				
CC		onstrate the layout tools, generation tools, etc.				
	books	, , , , , , , , , , , , , , , , , , , ,		<u> </u>		
		S IC Layout Concepts Methodologies and Tools, Newno	es 2000			
		s, The Art of Analog Layout, 2nd Edition, Prentice Hal				
	rence Book		-, -			
		Design, Layout, and Simulation by R. Jacob Baker. 3rd	Edition			
1. CIVI	Ob. Cheun D	coign, Layout, and omnutation by K. Jacob Daker. Stu	Lamon.			

M. TECH FIRST YEAR			
Course Code	AMTVL0214	LT P	Credit
Course Title	MEMS Sensor Design	300	03
Course Object	ive:	I	
1		brication	
	Technologies and Sensors/Transducers.		
2	To provide the knowledge about Mechanics of Bean	n and	
	Diaphragm Structures.		
3	To provide the knowledge about drag effect of a fluid	id, Air	
	damping and its models.		
4	To provide the knowledge of Electrostatic Actuation		
5	To provide the basic knowledge of MEMS Structure	es and	
D	Systems in RF applications.		
Pre-requisites:			
	Course Contents / Syllabus		
UNIT-I	INTRODUCTION TO MEMS		8 hours
	on Technologies, Materials and Substrates for M		
_ ·	Sensors/Transducers, Piezoresistive Effect, Piezoelec	tricity, Pie	ezoresistive
Sensor.			T
UNIT-II		HRAGM	8 hours
Ct 1 Ct :	STRUCTURES	C.	G'
	Hooke's Law. Stress and Strain of Beam Structure		
l .	ing Moment and the Moment of Inertia, Displacemer nding of Cantilever Beam Under Weight.	it of beam	Situdiales
UNIT-III	AIR DAMPING		8 hours
	luid: Viscosity of a Fluid, Viscous Flow of a Fluid, l	Drag Forg	
	ir Damping on Micro-Dynamics. Squeeze-film Air	_	
	neeze-film Air Damping, Damping of Perforated Th		
	sic Equations for Slide-film Air Damping, Couette-		
flow Model.	-1		,
UNIT-IV	ELECTROSTATIC ACTUATION		8 hours
	es, Normal Force, Tangential Force, Fringe Effects,	Electrosta	
l .	tuators: Parallel-plate Actuator, Capacitive sensors.		
	Step Voltage Driving, Negative Spring Effect and Vib		
UNIT-V	MEMS STRUCTURES AND SYSTEMS	IN RF	8 hours
	APPLICATIONS		
Signal Integrity	in RF MEMS, Microelectromechanical Resor		omb-Drive
l .	Resonators, Coupled-Resonator Bandpass Filters,		
	pelectromechanical Switches: Membrane Shunt Swit	ch, Cantil	ever Series
Switch.			
Course Outcome: After successful completion of this course students will be able to			
CO 1	Identify MEMs fabrication Technologies.		
i			

CO 2	Analyse Mechanics of Beam and Diaphragm Structures.	
CO 3	Explain drag effect of a fluid, Air damping and its models.	
CO 4	Design different Electrostatic Actuators.	
CO 5	Explain MEMS Structures and Systems in RF applications.	

Text books

- 1. Minhang Bao, 'Analysis and Design Principles of MEMS Devices', First edition 2005, Elsevier.
- 2. Nadim Maluf, KirtWilliums, 'An Introduction to Microelectromechanical Systems Engineering',2nd ed., Artech House microelectromechanical library.

Reference Books

1. RS Muller, Howe, Senturia and Smith, "Micro-sensors", IEEE Press.

M. TECH FIRST YEAR			
Course Code	AMTVL0215	LT P	Credit
Course Title	Nanoscale Devices: Modeling & Simulation	300	03
Course Object	ctive:		
1	To introduce novel MOSFET devices and understan	d the	
	advantages of multi-gate devices		
2	To introduce the concepts of nanoscale MOS transisto	or and	
	their performance characteristics		
3	To study the various Nano-scaled MOS transistor circuits	3	
4	To study radiation effects in SOI MOSFETs		
5	To study digital circuits and impact of device performan	ice on	
	digital circuits		
Course Contents / Syllabus			
UNIT-I	MOSFET SCALING		8 hours

MOSFET scaling, short channel effects - channel engineering - source/drain engineering - high k dielectric - copper interconnects - strain engineering, SOI MOSFET, multigate transistors - single gate - double gate - triple gate - surround gate, quantum effects - volume inversion - mobility - thresholdvoltage-intersub-bandscattering, multigatetechnology-mobility-gatestack.

UNIT-II MOS ELECTROSTATICS

8 hours

MOS Electrostatics – 1D – 2D MOS Electrostatics, MOSFET Current-Voltage Characteristics – CMOSTechnology – Ultimate limits, double gate MOS system – gate voltage effect – semiconductor thickness effect – asymmetry effect – oxide thickness effect – electron tunnel current – two dimensional confinements, scattering –mobility.

UNIT-III | SILICON NANOWIRE MOSFETS

10 hours

Silicon nanowire MOSFETs – Evaluation of I-V characteristics – The I-V characteristics for non-degenerate carrier statistics – The I-V characteristics for degenerate carrier statistics – Carbon nanotube – Band structure of carbon nanotube – Band structure of graphene – Physical structure of nanotube – Band structure of nanotube – Carbon nanotube FETs – Carbon nanotube MOSFETs – Schottky barrier carbon nanotube FETs – Electronic conduction in molecules – General model for ballistic nano transistors – MOSFETs with 0D, 1D, and 2D channels – Molecular transistors – Single electron charging – Single electron transistors

UNIT-IV RADIATION EFFECTS IN SOI MOSFETS

6 hours

Radiation effects in SOI MOSFETs, total ionizing dose effects – single-gate SOI – multigate devices, single event effect, scaling effects.

UNIT-V DIGITAL CIRCUITS

8 hours

Digital circuits – impact of device performance on digital circuits – leakage performance trade off – multi VT devices and circuits – SRAM design, analogcircuit design – transconductance - intrinsic gain – flicker noise – self heating –band gap voltage reference – operational amplifier – comparator designs, mixed signal – successive approximation DAC, RF circuits.

Course Outo	Course Outcome: After successful completion of this course students will be able to			
CO 1	Explain the MOS devices used below 10nm and beyond with an eye on the future			
CO 2	Explain the physics behind the operation of multi-gate systems.			
CO 3	To design circuits using nano-scaled MOS transistors with the physical insight of their functional characteristics			
CO 4	Explain radiation effects in SOI MOSFETs			
CO 5	Explain and designdigital circuits and impact of device performance on digital circuits			

Text books

- 1. J P Colinge, "FINFETs and other multi-gate transistors", Springer Series on integrated circuits and systems,2008
- 2. Mark Lundstrom, Jing Guo, "Nanoscale Transistors: Device Physics, Modelingand Simulation", Springer, 2006

Reference books

1. M S Lundstorm, "Fundamentals of Carrier Transport", 2nd Ed., Cambridge University Press, Cambridge UK, 2000

	M. TECH FIRST YEAR		
Course Code	AMTVL0216	LT P	Credit
Course Title	Physical Design & Automation	300	03
Course Object	tive:		
1	Students will know how to place the blocks and how to pa	rtition	
	the blocks while for designing the layout for IC.		
2	Students will be familiar to various kind of VLSI Automat	ion	
	Algorithms.		
3	Students will know the concepts of Physical Design Proces	ss	
	such as Floor planning, Placement algorithms.		
4	Students will learn Global Routing and Detailed Routing		
~	algorithms.		
5	Students will learn over the Cell Routing in detail.		
Pre-requisites	Basics of digital IC and data structures.		
TINITED T	Course Contents / Syllabus		0.1
UNIT-I	LOGIC SYNTHESIS & VERIFICATION	. 5.	8 hours
, ,	& Verification: Introduction combinational logic synthes are models for High- level synthesis.	is, Bina	ry decision
UNIT-II	VLSI AUTOMATION ALGORITHMS		0 hours
0 - 1		· · · · · · · · · · · · · · · · · · ·	8 hours
	n Algorithms: Partition: problem formulation, classificat		
algorithms, Grou	p migration algorithms, simulated annealing & evolution	omer	partitioning
UNIT-III	PLACEMENT, FLOOR PLANNING & PIN ASSIGNMENT	AENT	8 hours
	Planning & Pin assignment: problem-formulation, simulation		
· ·	r placement algorithms, constraint-based floor planning		
_	xed block & cell design. General & channel pin assignment.	ig, 1100	i plaining
UNIT-IV	GLOBAL ROUTING & DETAILED ROUTING		8 hours
	Problem formulation, classification of global routing algori	thme M	
	obe algorithm, Steiner Tree based algorithm, ILP based appr		aze routing
	problem formulation, classification of routing algorithms,		ver routing
_	ayer channel routing algorithms, three-layer channel routing	_	-
switchbox routing	· · · · · · · · · · · · · · · · · · ·		,
UNIT-V	OVER THE CELL ROUTING & VIA MINIMIZATION	N	8 hours
Over the Cell R	outing & via Minimization: two layers over the cell rou	ters, cor	strained &
	minimization Compaction: problem formulation, one-dimen	-	
	sed Compaction, hierarchical compaction.		1
Course Outco	me: After successful completion of this course students	will be a	ble to
CO 1	Know how to place the blocks and how to partition the	blocks	
	while for designing the layout for IC.		
CO 2	Explain VLSI Design Automation.		
CO 3	Explain the concepts of Physical Design Process such as	Floor	
	planning, Placement and Routing.		

CO 4	AnalyzeGlobal Routing and Detailed Routing algorithms.
CO 5	Decompose large problem into pieces via minimization.
Text books	
1. Naveed	Sherwani, "Algorithms for VLSI Physical Design Automation", Kluwer
Academic	Publisher, Second edition.
Reference Boo	oks
1. Christoph	nMeinel&ThorstemTheobold, "Algorithm and Data Structures for VLSI
Design", l	KAP 2002.
2. Rolf Drec	hsheler: "Evolutionary Algorithm for VLSI", second edition
3. Trimburge	er," Introduction to CAD for VLSI", Kluwer Academic publisher, 2002.

M. TECH FIRST YEAR				
Course Code	AMTVL0217	LT	P Credit	
Course Title	Embedded Microcontrollers	3 0 0	0 03	
Course Objec	tive:			
1	To provide the Basic knowledge of interfa	icing wi	rith	
	Embedded System.			
2	To analyse the process design of embedded sys	stem.		
3	To realize the architecture of PIC 16F Microcontroller			
	Series.			
4 To familiar with the fundamentals of ARM Processor				
	Cortex M3 & M4.			
5	To apply the knowledge of ARM Instruction	on Set f	for	
programming.				
Pre-requisites: Digital System design, 8051 Microcontroller				
Course Contents / Syllabus				
UNIT-I	TYPICAL EMBEDDED SYSTEMS		8 hours	

Core of the embedded system, General purpose and domain specific processor, ASICs, PLDs, Commercial off the shelf Components (COTS), Memory: RAM, ROM, Memory according to the type of interface, Memory Shadowing, Memory selection for embedded system, Sensors and actuators, Introduction to Communication Interface (Onboard and External).

UNIT-II EMBEDDED SYSTEMS DESIGN PROCESS 8 hours

Embedded system project development, Design issues and co-design issues in system development process, The Embedded Design Life Cycle, Selection Process, The Partitioning Decision (Hardware and Software partitioning), The Development and Debugging Environment (use of target machine or its emulator and In- Circuit emulator), Special Software Techniques, Introduction to BDM, JTAG, and Nexus.

Introduction to PIC Microcontroller families (8/16 and 32 bit), PIC 16F series family overview of architecture and peripherals, Pin diagram and Architecture of PIC16F84/PIC16F84A Microcontroller, Memory organization, configuration, memory addressing, and special function registers, parallel and serial ports, timer and counters. Special features of PIC16F84A (OSC Selection, RESET - Power-on Reset (POR), Power-up Timer (PWRT), Oscillator Start-up Timer (OST), Interrupts, Watchdog Timer (WDT), SLEEP, Code Protection, ID Locations, In-Circuit Serial Programming, interrupts).

UNIT-IV ARCHITECTURE OF ARM CORTEX M3 AND M4 8 hours PROCESSORS

Architectural overview of PIC 16F877/PIC 16F887A.

Introduction to Cortex-M3 and Cortex-M4 processors (Processor architecture, Instruction set, Block diagram, Memory system, Interrupt and exception support). Programmer's model, Operation modes, Registers, Memory System, features, stack memory, memory requirements, endianness, bit band operations, access permissions and attributes, memory barriers, Low power design and features, low power application development, overview of exceptions and interrupts, exception types and interrupt management, vector table, exception sequence, use of NVIC register, SCB register and other special registers for exception and

interrupt control, configuration control and auxiliary control registers.					
UNIT-V	UNIT-V INSTRUCTION SETOF CORTEX M3 AND M4 8 hours				
	PROCESSORS				

Evolution of ARM ISA, Comparison of the instruction set in ARM Cortex-M Processors, Unified Assembly Language, Addressing modes, Instruction set, Program flow control (branch, conditional branch, conditional execution, and function calls), Multiply accumulate (MAC) instructions, Divide instructions, Memory barrier instructions, Exception-related instructions, Sleep mode-related instructions, Other functions, Introduction to Cortex-M4 processor support for Enhanced DSP instructions, Writing C and Assembly language programs.

Course Outcome: After successful completion of this course students will be able to

CO 1	Explain the Basic knowledge of interfacing with
	Embedded System.
CO 2	Analyse the process design of embedded system.
CO 3	Realize the architecture of PIC 16F Microcontroller
	Series.
CO 4	Familiar with the fundamentals of ARM Processor Cortex M3 & M4.
CO 5	Apply the knowledge of ARM Instruction Set for programming.

Text books

- 1. Introduction to Embedded Systems, A Cyber physical approach, Edward A. Lee and Senjit A. Seshia.
- 2. Embedded Systems Design: An Introduction to Processes, Tools, and Techniques, by Arnold S. Berger, CMP Books.

Reference Books

- 1. Designing Embedded Systems with PIC Microcontrollers: Principles and Applications, 2nd Edition, Tim Wilmshurst, Elsevier Publication.
- **2.** PIC Microcontroller and Embedded Systems Using Assembly and C for PIC 18 by Muhammad Ali Mazidi, Rolin D. McKinlay and Danny Causey, Pearson Publication.
- **3.** The Definitive Guide to ARM Cortex M3 and Cortex-M4 Processors, Third Edition, Joseph Yiu, Elsevier Publication, 2015.
- 4. ARM Assembly Language Fundamentals and Techniques, William Hohl and Christopher Hinds, CRC Press, 2015.

	M. TECH FIRST YEAR		
Course Code	AMTVL0218	LTP	Credit
Course Title	Real Time Operating System	3 0 0	03
Course Objecti			00
1	To provide the concept of real time operating system.		
2	To analyse the task scheduling method & I/O system.		
3	To realize the firmware design process.		
4	To familiar with the different types of management sy	stem	
	for RTOS.		
5	To explain the concept of RTX.		
Pre-requisites:	Digital System design, Microcontroller.		
	Course Contents / Syllabus		
UNIT-I	OPEN SOURCE RTOS		8 hours
	Real-time concepts, Hard Real time and Soft Rea	ıl-time, I	
	urpose OS & RTOS, Basic architecture of an RTOS, S		
Inter-process con	nmunication, Performance Matric in scheduling	models,	Interrupt
management in R	TOS environment, Memory management, File syst	tems, I/C	Systems,
	advantage of RTOS. POSIX standards, RTOS Issues		
	stem, RTOS comparative study. Converting a normal		
	nai basics. Overview of Open source RTOS for Embe	edded sys	stems (Free
	(i) and application development		
UNIT-II	Vx WORKS/ FREE RTOS		8 hours
	OS Scheduling and Task Management – Real time sch	•	
	Communication, Pipes, Semaphore, Message Queue, S		
1 *	tems – General Architecture, Device Driver Studies, Dr	river Mo	dule
	mentation of Device Driver for a peripheral.		101
UNIT-III	EMBEDDED FIRMWARE DESIGN AND DEVELOPMENT		10 hours
Embedded Firmw	are Design Approaches, Super-loopbased approach, En		
		mhedded	
System based appr			Operating
	oach, Programming in Embedded C, Integrated develo		Operating
(IDE), Overview o	oach, Programming in Embedded C, Integrated develof IDEs for Embedded System Development.	opment ei	Operating nvironment
(IDE), Overview o UNIT-IV	oach, Programming in Embedded C, Integrated develor f IDEs for Embedded System Development. EMBEDDED SYSTEM DESIGN WITH FREE RT	FOS	Operating nvironment 6 hours
(IDE), Overview o UNIT-IV Queue Management	oach, Programming in Embedded C, Integrated develor of IDEs for Embedded System Development. EMBEDDED SYSTEM DESIGN WITH FREE RT ont, Characteristics of a Queue, Working with Landau Control of the Con	FOS rge Data	Operating nvironment 6 hours Interrupt
(IDE), Overview o UNIT-IV Queue Management, Que	oach, Programming in Embedded C, Integrated develor of IDEs for Embedded System Development. EMBEDDED SYSTEM DESIGN WITH FREE RT ont, Characteristics of a Queue, Working with Laures within an Interrupt Service Routine, Critical Section	FOS rge Data	Operating nvironment 6 hours Interrupt
(IDE), Overview of UNIT-IV Queue Management, Que the Scheduler, Res	oach, Programming in Embedded C, Integrated develor of IDEs for Embedded System Development. EMBEDDED SYSTEM DESIGN WITH FREE RT ont, Characteristics of a Queue, Working with Landau Control of the Con	FOS rge Data	Operating nvironment 6 hours Interrupt Suspending
(IDE), Overview of UNIT-IV Queue Management, Que the Scheduler, Res UNIT-V	oach, Programming in Embedded C, Integrated develor of IDEs for Embedded System Development. EMBEDDED SYSTEM DESIGN WITH FREE RT ont, Characteristics of a Queue, Working with Laues within an Interrupt Service Routine, Critical Sectionarce Management, Memory Management. RTX	FOS rge Data ons and S	Operating nvironment 6 hours Interrupt Suspending 8 hours
(IDE), Overview of UNIT-IV Queue Management, Que the Scheduler, Res UNIT-V RTX structure, RT	oach, Programming in Embedded C, Integrated develor of IDEs for Embedded System Development. EMBEDDED SYSTEM DESIGN WITH FREE RT ont, Characteristics of a Queue, Working with Larues within an Interrupt Service Routine, Critical Sectionarce Management, Memory Management.	rge Data ons and S Manager	Operating nvironment 6 hours Interrupt Suspending 8 hours ment APIs,
(IDE), Overview of UNIT-IV Queue Management, Que the Scheduler, Res UNIT-V RTX structure, RT Task Priority Scheduler	oach, Programming in Embedded C, Integrated develor of IDEs for Embedded System Development. EMBEDDED SYSTEM DESIGN WITH FREE RT ont, Characteristics of a Queue, Working with Larues within an Interrupt Service Routine, Critical Section ource Management, Memory Management. RTX X files, RTX task and time management, Simple Time	rge Data ons and S Manager Interrup	6 hours Interrupt Suspending 8 hours ment APIs, ot, Mutex,
(IDE), Overview of UNIT-IV Queue Management, Que the Scheduler, Res UNIT-V RTX structure, RT Task Priority Scheduler	oach, Programming in Embedded C, Integrated develor of IDEs for Embedded System Development. EMBEDDED SYSTEM DESIGN WITH FREE RT ont, Characteristics of a Queue, Working with Larues within an Interrupt Service Routine, Critical Section ource Management, Memory Management. RTX X files, RTX task and time management, Simple Time name in RTX, Inter-Task Communication, Event,	rge Data ons and S Manager Interrup	6 hours Interrupt Suspending 8 hours ment APIs, ot, Mutex,
(IDE), Overview of UNIT-IV Queue Management, Que the Scheduler, Res UNIT-V RTX structure, RT Task Priority Schemaphore, Maille CMSIS-RTOS.	oach, Programming in Embedded C, Integrated develor of IDEs for Embedded System Development. EMBEDDED SYSTEM DESIGN WITH FREE RT ont, Characteristics of a Queue, Working with Larues within an Interrupt Service Routine, Critical Section ource Management, Memory Management. RTX X files, RTX task and time management, Simple Time name in RTX, Inter-Task Communication, Event,	rge Data ons and S Manager Interruphs, Arch	6 hours Interrupt Suspending 8 hours ment APIs, ot, Mutex, itecture of

CO 2	Analyse the task scheduling method & I/O system.	
CO 3	Realize the firmware design process.	
CO 4	Familiar with the different types of management system for RTOS.	
CO 5	Explain the concept of RTX.	

Text books

- 1. VenkateswaranSreekrishnan,"Essential Linux Device Drivers", Ist Kindle edition, Prentice Hall, 2008
- 2. Jonathan W. Valvano, "Real-Time Operating Systems for ARM Cortex-M Microcontrollers" Jonathan Valvano; 4 edition

Reference Books

- **1.** Jerry Cooperstein, "Writing Linux Device Drivers: A Guide with Exercises", J. Cooperstein publishers, 2009
- **2.** Qing Li and Carolyn Yao,"Real Time Concepts for Embedded Systems" Qing Li, Elsevier ISBN:1578201241 CMP Books © 2003
- **3.** "Using the FreeRTOS Real Time Kernel" From Free RTOS.
- 4. Sam Siewert, "Real-Time Embedded Systems And Components".

Course Code			
Course Cour	AMTVL0219 I	TP	Credit
Course Title	System On Chip (SOC) Design using ARM 3	0 0	03
Course Objectiv	ve:		
1	Study the Architecture of Arm Cortex-M0 Processor.		
2	Describe the AMBA 3 AHB-Lite Bus Architecture	,	
	VGA, GPIO and 7-Segment UART Peripheral		
3	Learn the Programming of SoC Using C Language.		
4	Compare ARM Cortex-A9 Processor with other		
	processor.		
5	Implement and compare an AXI UART and AXI- Stream Peripheral		
Pre-requisites: 1	l. Basics of HDL (Verilog /VHDL)		
_	2. Basics of Microcontroller Assembley language Progra	ımming	5
	Course Contents / Syllabus	_	
OI VII I	INTRODUCTION TO SYSTEM-ON-CHIP	8	3 hours
	DESIGN AND AND AND AND AND AND AND AND AND AN	1	
	SoCs, CPUs and MCUs, Arm Cortex-M0 Processor Ar	chitect	
@1 (II II	PROGRAMMING AN SOC		8 hours
	ite Bus Architecture, AHB VGA Peripheral, AHB		
	7-Segment Peripherals, Interrupt Mechanisms, Prog	grammı	ng an SoC
Using C Language.			0.1
CI (II III	ARM CORTEX-A9 PROCESSOR	/D. I.G. A	8 hours
Arm CMSIS and S ARM Cortex-A9 Pa	Software Drivers, Arm Development Studio, ARMv7-A	/R ISA	Overview,
	AMBA AXI4		8 hours
	s Architecture, Design and Implementation of an A	XI4-Li	
	DR Memory Controller		
UNIT-V	IMPLEMENTATION OF AN AXI UART AND AXI-STREAM		8 hours
Design and Implem	nentation of an AXI UART and AXI-Stream Peripheral,	AXI4-	Stream and
	IDMI Input Peripheral, System Debugging.		
Course Outcom	ne: After completion of this course students will be al	ole to	
	Explain Arm Cortex-M0 Processor Architecture.		
CO 2	RecognizeAMBA 3 AHB-Lite Bus Architecture	,	
	VGA, GPIO and 7-Segment UART Peripheral.		
CO 3	Program SoC Using C Language.		
CO 4	Explain ARM Cortex-A9 Processor.		
CO 5	Design and Implement an AXI UART and AXI-Stream Peripheral.		
Text books			

- 1. ARM System-on-Chip Architecture by Steve B. Furber
- 2. ARM Assembly Language: Fundamentals and Techniques by William Hohl
- 3. The Definitive Guide to the ARM Cortex-M0 by Joseph Yiu

Reference Books

- 1. Computer System Design: System-On-Chip Michael J. Flynn and Wayne Luk, Wiely India.
- 2. Modern VLSI Design System on Chip Design Wayne Wolf, Prentice Hall,
- 3. Design of System on a Chip: Devices and Components, Ricardo Reis, Springer
- 4. System on Chip Verification Methodologies and Techniques: Prakash Rashinkar, Peter Paterson and Leena Singh L, Kluwer Academic Publishers

Link:	
Unit 1	https://www.youtube.com/watch?v=PRQXzjTrCJY https://www.youtube.com/watch?v=HNbeVvfFKsQ
Unit 2	https://www.youtube.com/watch?v=j2NI4AXRs1Uhttps://www.youtube.com/watch?v=4VRtujwa b8&list=PL90187D2B8F5AC28F&index=5
Unit 3	https://www.youtube.com/watch?v=4VRtujwa_b8
Unit 4	https://www.youtube.com/watch?v=mYP5SxDEjrM https://www.youtube.com/watch?v=QQY-h0HGHnI https://www.youtube.com/watch?v=tEvtb- mdJ4s&list=PL90187D2B8F5AC28F&index=16
Unit 5	https://www.youtube.com/watch?v=nbWWMPPC8aE https://www.youtube.com/watch?v=MANrmky5DfE